# **SIEMENS**

TrilithIC™ BTS 771

#### Overview

#### **Features**

- · Quad switch driver
- · Free configurable as bridge or quad-switch
- Optimized for DC motor management applications
- Ultra low *R*<sub>DS ON</sub> @ 25 °C:

High-side switch: typ. 85 m $\Omega$ , Low-side switch: typ. 40 m $\Omega$ 

- · Very high peak current capability
- Very low quiescent current
- Space- and thermal optimized power P-DSO-Package
- Load and GND-short-circuit-protected
- Operates up to 40 V
- · Status flag diagnosis
- Overtemperature shut down with hysteresis
- Short-circuit detection and diagnosis
- Open-load detection and diagnosis
- C-MOS compatible inputs
- Internal clamp diodes
- Isolated sources for external current sensing
- Over- and under-voltage detection with hysteresis

Туре	Ordering Code	Package		
BTS 771	Q67007-A9274	P-DSO-28-9		

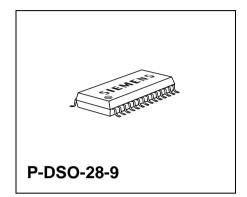
### **Description**

The **BTS 771** is a **TrilithIC** contains one double high-side switch and two low-side switches in **one P-DSO-28-9** -Package.

# "Silicon instead of heatsink" becomes true

The ultra low  $R_{\rm DS~ON}$  of this device avoids powerdissipation. It saves costs in mechanical construction and mounting and increases the efficiency.

The high-side switches are produced in the **SIEMENS SMART SIPMOS**® technology. It is fully protected and contains the signal conditioning circuitry for diagnosis. (The comparable standard high-side product is the **BTS 621L1**.)



For minimized  $R_{\rm DS\,ON}$  the two low-side switches are produced in the **SIEMENS Millifet** logic level technology (The comparable standard product is the **BUZ 103AL**).

Each drain of these three chips is mounted on separated leadframes (see **P-DSO-28-9** pin configuration). The sources of all four power transistors are connected to separate pins.

So the **BTS 771** can be used in H-Bridge configuration as well as in any other switch configuration.

Moreover, it is possible to add current sense resistors.

All these features open a broad range of automotive and industrial applications.

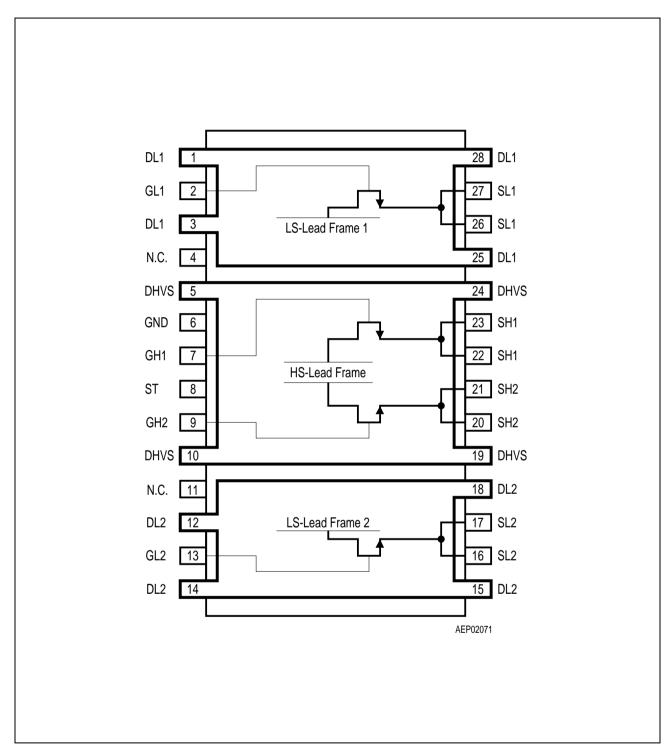


Figure 1 Pin Configuration (top view)

# **Pin Definitions and Functions**

Pin No.	Symbol	Function
1, 3, 25, 28	DL1	Drain of low-side switch1 Leadframe 1 1)
2	GL1	Gate of low-side switch1
4	N.C.	not connected
5, 10, 19, 24	DHVS	Drain of high-side switches and power supply voltage Leadframe 2 1)
6	GND	Ground
7	GH1	Gate of high-side switch1
8	ST	Status of high-side switches; open Drain output
9	GH2	Gate of high-side switch2
11	N.C.	not connected
12, 14, 15, 18	DL2	Drain of low-side switch2 Leadframe 3 1)
13	GL2	Gate of low-side switch2
16, 17	SL2	Source of low-side switch2
20, 21	SH2	Source of high-side switch2
22, 23	SH1	Source of high-side switch1
26, 27	SL1	Source of low-side switch1

<sup>1)</sup> To reduce the thermal resistance these pins are direct connected via metal bridges to the leadframe.

# **Bold type: Pin needs power wiring**

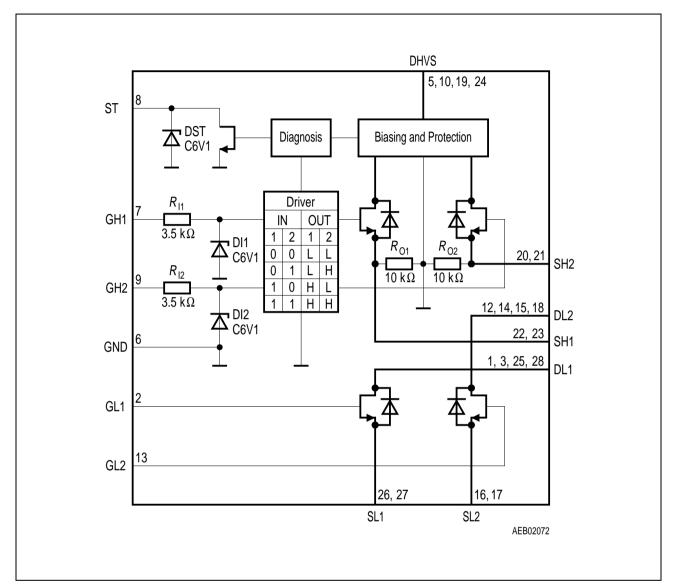


Figure 2 Block Diagram

### **Circuit Description**

### **Input Circuit**

The control inputs GH1,2 consist of TTL/CMOS compatible Schmitt-Triggers with hysteresis. Buffer amplifiers are driven by these stages and convert the logic signal into the necessary form for driving the power output stages.

The inputs GH1 and GH2 are connected to a standard N-channel logic level power-MOS gate.

### **Output Stages**

The output stages consist of an ultra low  $R_{\rm DS\,ON}$  Power-MOS H-Bridge. Protective circuits make the outputs short circuit proof to ground and load short circuit proof. Positive and negative voltage spikes, which occur when driving inductive loads, are limited by integrated power clamp diodes.

### Short Circuit Protection (valid only for the high-side switches)

The outputs are protected against

- output short circuit to ground, and
- overload (load short circuit).

An internal OP-Amp controls the Drain-Source-Voltage of the HS-Switches by comparing the DS-Voltage-Drop with an internal reference voltage. Above this trippoint the OP-Amp reduces the output current depending on the junction temperature and the drop voltage.

In the case of overloaded high-side switches the status output is set to low.

If the HS-Switches are in OFF-state-Condition internal resistors Ro1,2 from SH1,2 to GND pull the voltage at SH1,2 to low values. On each output pin SH1 and SH2 an output examiner circuit compares the output voltages with the internal reference voltage VEO. This results in switching the status output to low. In H-Bridge condition this feature can be used to protect the low-side switches against short circuit during the OFF-period.

### **Overtemperature Protection (valid only for the high-side-switches)**

The chip also incorporates an overtemperature protection circuit with hysteresis which switches off the output transistors and sets the status output to low.

### **Undervoltage-Lockout (UVLO)**

When  $V_{\rm S}$  reaches the switch-on voltage  $V_{\rm UVON}$  the IC becomes active with a hysteresis. The High-Side output transistors are switched off if the supply voltage  $V_{\rm S}$  drops below the switch off value  $V_{\rm UVOFF}$ .

### Overvoltage-Lockout (OVLO)

When  $V_{\rm S}$  reaches the switch-off voltage  $V_{\rm OVOFF}$  the High-Side output transistors are switched off with a hysteresis. The IC becomes active if the supply voltage  $V_{\rm S}$  drops below the switch-on value  $V_{\rm OVON}$ .

### **Open Load Detection**

Open load is detected by current measurement. If the output current drops below an internal fixed level the error flag is set with a delay.

### **Status Flag**

Various errors as listed in the table "Diagnosis" are detected by switching the open drain output ST to low.



# **Truthtable and Diagnosis (valid only for the High-Side-Switches)**

Flag	GH1	GH2	SH1	SH2	ST	Remarks
	Inputs		Outputs			
	0	0	L	L	1	stand-by mode
Normal operation;	0	1	L	Н	1	switch2 active
identical with functional truth table	1	0	Н	L	1	switch1 active
	1	1	Н	Н	1	both switches active
Open load at high-side switch1	0	0	Z	L	1	
•	0	1	Z	Н	1	
	1	Χ	Н	X	0	detected
Open load at high-side switch2	0	0	L	Z	1	
	1	0	Н	Z	1	
	X	1	X	Н	0	detected
Short circuit to DHVS at high-side switch1	0	0	Н	L	0	detected
	0	1	Н	Н	1	
	1	X	Н	X	1	
Short circuit to DHVS at high-side switch2	0	0	L	Н	0	detected
	1	0	Н	Н	1	
	X	1	X	Н	1	
Overtemperature high-side switch1	0	Х	L	Х	1	
	1	X	L	X	0	detected
Overtemperature high-side switch2	Х	0	Х	L	1	
	X	1	X	L	0	detected
Overtemperature both high-side switch	0	0	L	L	1	
,	X	1	L	L	0	detected
	1	X	L	L	0	detected
Over- and Under-Voltage	Х	Х	L	L	1	not detected

Inputs: Outputs: Status:

0 = Logic LOW Z = Output in tristate condition 1 = No error

1 = Logic HIGH L = Output in sink condition 0 = Error

X = don't care H = Output in source condition

X = Voltage level undefined

### **Electrical Characteristics**

### **Absolute Maximum Ratings**

 $-40 \, ^{\circ}\text{C} < T_{j} < 150 \, ^{\circ}\text{C}$ 

Parameter	Symbol	Limit Values		Unit	Remarks
		min.	max.		

### High-Side-Switches (Pins DHVS, GH1,2 and SH1,2)

Supply voltage	$V_{\mathtt{S}}$	- 0.3	43	V	_
HS-drain current	$I_{DHS}$	<b>– 10</b>	*	Α	* internally limited
HS-input current	$I_{GH}$	- 2	2	mA	Pin GH1 and GH2
HS-input voltage	$V_{GH}$	<b>- 10</b>	16	V	Pin GH1 and GH2

### **Status Output ST**

Status Output current	$I_{ST}$	- 5	5	mΑ	Pin ST
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# Low-Side-Switches (Pins DL1,2, GL1,2 and SL1,2)

Break-down voltage	$V_{(BR)DSS}$	50	_	V	$V_{\rm GS}$ = 0 V; $I_{\rm D}$ <= 1 mA
LS-drain current	$I_{ t DLS}$	_	10	Α	_
LS-drain current	$I_{ extsf{DLS}}$	_	20	Α	<i>t</i> < 1 ms; v < 0.1
LS-drain current	$I_{ extsf{DLS}}$	_	30	А	<i>t</i> < 0.1 ms; v < 0.1
IS-input voltage	$V_{GL}$	<b>– 10</b>	14	V	Pin GL1 and GL2

### **Temperatures**

Junction temperature	$T_{j}$	- 40	150	°C	_
Storage temperature	$T_{stg}$	<b>- 50</b>	150	°C	_

# Thermal Resistances (one HS-LS-Path active)

LS-junction case	$R_{thjCLS}$	_	20	K/W	measured to pin3 or 12
HS-junction case	$R_{thjCHS}$	_	20	K/W	measured to pin19
Junction ambient	$R_{thja}$	_	60	K/W	_

Note: Maximum ratings are absolute ratings; exceeding any one of these values may cause irreversible damage to the integrated circuit.

# **Operating Range**

Parameter	Symbol	Limit Values		Unit	Remarks	
		min.	max.			
Supply voltage	$V_{S}$	$V_{\sf UVOFF}$	34	V	After $V_{\rm S}$ rising above $V_{\rm UVON}$	
Input voltages	$V_{GH}$	- 0.3	15	V	-	
Input voltages	$V_{GL}$	- 9	13	V	-	
Output current	$I_{ST}$	0	2	mA	_	
HS-junction temperature	$T_{jHS}$	- 40	150	°C	_	
LS-junction temperature	$T_{jLS}$	- 40	150	°C	_	

Note: In the operating range the functions given in the circuit description are fulfilled.

### **Electrical Characteristics**

 $I_{\rm SH1}$  =  $I_{\rm SH2}$  =  $I_{\rm SL1}$  =  $I_{\rm SL2}$  = 0 A; - 40 °C <  $T_{\rm j}$  < 150 °C; 8 V >  $V_{\rm S}$  > 18 V unless otherwise specified

Parameter	Symbol	Limit Values			Unit	Test Condition
		min.	typ.	max.		

# **Current Consumption**

Quiescent current	$I_{\mathbb{S}}$	_	16	30	μΑ	GH1 = GH2 = L $V_{\rm S}$ = 13.2 V $T_{\rm j}$ = 25 °C
Quiescent current	$I_{\mathbb{S}}$	_	_	35	μΑ	GH1 = GH2 = L $V_{\rm S}$ = 13.2 V
Supply current	$I_{\mathbb{S}}$	_	2	3.5	mA	GH1 or GH2 = H
Supply current	$I_{\mathbb{S}}$	_	4	7	mA	GH1 and GH2 = H

# **Under Voltage Lockout (UVLO)**

Switch-ON voltage	$V_{UVON}$	_	5.4	7	V	$V_{ m S}$ increasing
Switch-OFF voltage	$V_{UVOFF}$	3.5	4.2	_	V	$V_{ m S}$ decreasing
Switch ON/OFF hysteresis	$V_{\sf UVHY}$	_	1.2	_	V	$V_{ m UVON} - V_{ m UVOFF}$

# **Over Voltage Lockout (OVLO)**

Switch-OFF voltage	$V_{OVOFF}$	36	37.8	43	V	$V_{\rm S}$ increasing
Switch-ON voltage	$V_{OVON}$	35	37.1	_	V	$V_{ m S}$ decreasing
Switch OFF/ON hysteresis	$V_{OVHY}$	_	0.7	_	٧	$V_{OVOFF} - V_{OVON}$

# **Short Circuit of Highside Switch to GND**

Initial peak SC current	$I_{SCP}$	11	18	25	Α	<i>T</i> <sub>j</sub> = − 40 °C
Initial peak SC current	$I_{\sf SCP}$	9	14	22	Α	<i>T</i> <sub>j</sub> = 25 °C
Initial peak SC current	$I_{\sf SCP}$	5	8	14	Α	<i>T</i> <sub>j</sub> = 150 °C

# **Electrical Characteristics** (cont'd)

 $I_{\rm SH1}$  =  $I_{\rm SH2}$  =  $I_{\rm SL1}$  =  $I_{\rm SL2}$  = 0 A; - 40 °C <  $T_{\rm j}$  < 150 °C; 8 V >  $V_{\rm S}$  > 18 V unless otherwise specified

Parameter	Symbol	Lir	Limit Values			Test Condition
		min.	typ.	max.		

# Short Circuit of Highside Switch to $V_{ m S}$

OFF-state examiner-voltage	$V_{EO}$	2	3	4	V	$V_{\mathrm{GH}}$ = 0 V
Output pull-down-resistor	$R_{O}$	4	11	30	kΩ	

# **Open Circuit Detection of Highside Switch**

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# **Switching Times of Highside Switch**

Switch-ON-time; to 90% $V_{\rm SH}$	t <sub>ON_H</sub>	_	0.2	0.4	ms	resistive load $I_{SH}$ = 1 A; $V_{S}$ = 12 V
Switch-OFF-time; to 10% $V_{\rm SH}$	$t_{OFF\_H}$	_	0.2	0.4	ms	resistive load $I_{SH}$ = 1 A; $V_{S}$ = 12 V

# Control Inputs of Highside Switches GH 1, 2

H-input voltage	$V_{GHH}$	_	2.8	3.5	V	_
L-input voltage	$V_{GHL}$	1.5	2.3	_	V	_
Input voltage hysterese	$V_{GHHY}$	_	0.5	_	V	_
H-input current	$I_{GHH}$	20	60	80	μΑ	$V_{\mathrm{GH}}$ = 5 V
L-input current	$I_{GHL}$	1	25	50	μΑ	$V_{\mathrm{GH}}$ = 0.4 V
Input series resistance	$R_{I}$	2.5	3.5	6	kΩ	_
Zener limit voltage	$V_{GHZ}$	5.4	_	_	V	$I_{\rm GH}$ = 1.6 mA

# **Status Flag Output ST of Highside Switch**

Low output voltage	$V_{\mathtt{STL}}$	_	0.25	0.6	V	$I_{\rm ST}$ = 1.6 mA
Leakage current	$I_{ m STLK}$	_	0.5	10	μΑ	$V_{\mathrm{ST}}$ = 5 V
Zener-limit-voltage	$V_{ m STZ}$	5.4	_	_	V	$I_{\rm ST}$ = 1.6 mA

# Electrical Characteristics (cont'd)

 $I_{\rm SH1}$  =  $I_{\rm SH2}$  =  $I_{\rm SL1}$  =  $I_{\rm SL2}$  = 0 A; - 40 °C <  $T_{\rm j}$  < 150 °C; 8 V >  $V_{\rm S}$  > 18 V unless otherwise specified

Parameter	Symbol	Lin	Limit Values		Unit	Test Condition
		min.	typ.	max.		

# **Control Inputs of Lowside Switches GL1, 2**

Gate-threshold-voltage	$V_{GL(th)}$	0.8	1.6	2.5	V	$V_{\rm GL} = V_{\rm DSL};$ $I_{\rm DL} = 1 \ {\rm mA}$
Transconductance	$g_{fs}$	_	5	_	S	$V_{\rm DSL}$ = 20 V; $I_{\rm DL}$ = 20 A

# **Switching Times of Lowside Switch**

Switch-ON delay time; $V_{\rm GS}$ = 5 V; $R_{\rm GS}$ = 50 $\Omega$	$t_{\sf d\_ON\_L}$	_	25	40	ns	resistive load $I_{SL}$ = 1 A; $V_{S}$ = 12 V
Switch-ON time; $V_{\rm GS}$ = 5 V; $R_{\rm GS}$ = 50 $\Omega$	$t_{ON\_L}$	_	95	140	ns	resistive load $I_{SL}$ = 1 A; $V_{S}$ = 12 V
Switch-OFF delay time; $V_{\rm GS}$ = 5 V; $R_{\rm GS}$ = 50 $\Omega$	$t_{\sf d\_OFF\_L}$	_	140	190	ns	resistive load $I_{SL}$ = 1 A; $V_{S}$ = 12 V
Switch-OFF time; $V_{\rm GS}$ = 5 V; $R_{\rm GS}$ = 50 $\Omega$	$t_{OFF\_L}$	_	85	115	ns	resistive load $I_{SL}$ = 1 A; $V_{S}$ = 12 V

#### **Thermal Shutdown**

Thermal shutdown junction temperature	$T_{jSD}$	155	_	190	°C	_
Thermal switch-on junction temperature	$T_{jSO}$	150	_	180	°C	_
Temperature hysteresis	$\Delta T$	_	10	_	°C	$\Delta T = T_{\rm jSD} - T_{\rm jSO}$

# Electrical Characteristics (cont'd)

 $I_{\rm SH1}$  =  $I_{\rm SH2}$  =  $I_{\rm SL1}$  =  $I_{\rm SL2}$  = 0 A; - 40 °C <  $T_{\rm j}$  < 150 °C; 8 V >  $V_{\rm S}$  > 18 V unless otherwise specified

Parameter	Symbol	Limit Values			Unit	Test Condition
		min.	typ.	max.		

### **Output Stages**

Leakage current of highside switch	$I_{HSLK}$	_	5	12	μΑ	$V_{\rm GH} = V_{\rm SH} = 0 \text{ V}$
Leakage current of lowside switch	$I_{LSLK}$	_	20	100	μΑ	$V_{\rm GL}$ = 0 V $V_{\rm DS}$ = 18 V
Clamp-diode of highside switch; Forward-Voltage	$V_{FH}$	_	0.8	1.5	V	$I_{FH} = 3 \; A$
Clamp-diode leakage- current ( $I_{\text{FH}}$ + $I_{\text{SH}}$ ) of highside switch	$I_{LKCL}$	_	2	10	mA	I <sub>FH</sub> = 3 A
Clamp-diode of lowside switch; forward-voltage	$V_{\sf FL}$	_	0.8	1.5	V	$I_{FL} = 3 \; A$
Static drain-source on-resistance of highside switch	$R_{ extsf{DS ON H}}$	_	85	110	mΩ	$I_{\rm SH} = 1 \; {\rm A}$ $T_{\rm j} = 25 \; {\rm ^{\circ}C}$
Static drain-source on-resistance of lowside switch	R <sub>DS ON L</sub>	_	40	55	mΩ	$I_{\rm SL}$ = 1 A; $V_{\rm GL}$ = 5 V $T_{\rm j}$ = 25 °C
Static path on-resistance	$R_{DSON}$	_	_	300	mΩ	$R_{\rm DSONH} + R_{\rm DSONL};$ $I_{\rm SH} = 1$ A

Note: The listed characteristics are ensured over the operating range of the integrated circuit. Typical characteristics specify mean values expected over the production spread. If not otherwise specified, typical characteristics apply at  $T_A = 25$ °C and the given supply voltage.

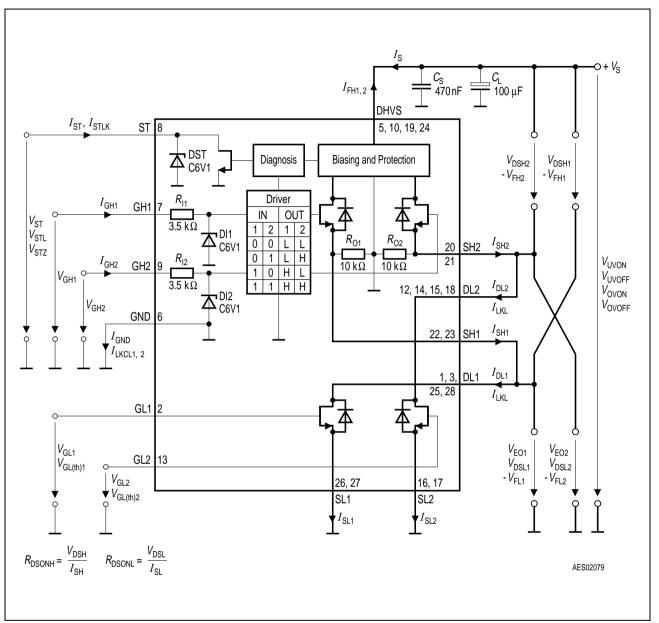


Figure 3 Test Circuit

HS-Source-Current	•		Named during Leakage-Cond.
$I_{SH1,2}$	$I_{SCP}$	$I_{\sf OCD}$	$I_{HSLK}$

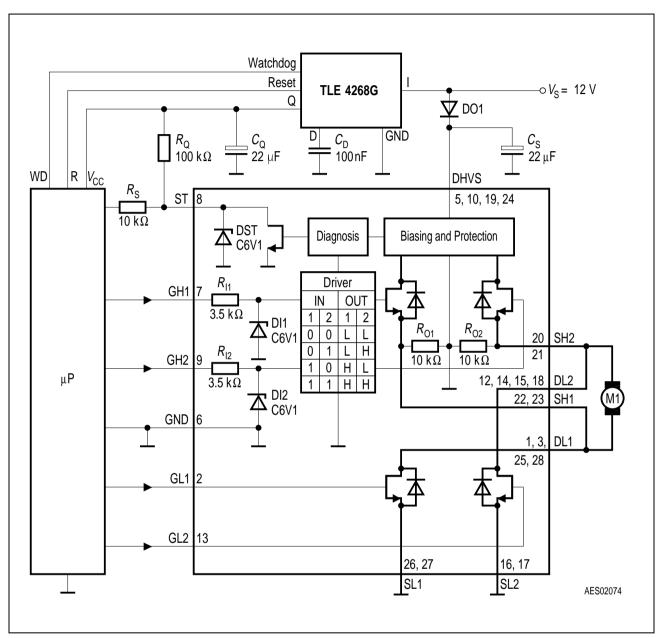
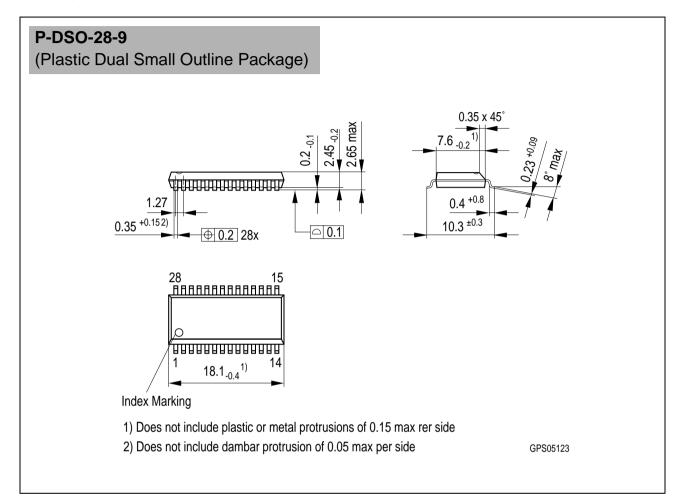


Figure 4 Application Circuit

# **Package Outlines**



### **Sorts of Packing**

Package outlines for tubes, trays etc. are contained in our Data Book "Package Information".

SMD = Surface Mounted Device

Dimensions in mm